



Qualcomm Technologies, Inc.

Samsung portable handset (FCC ID: A3LSMN976V) RF Exposure Compliance Test Report_Appendix G: Test Setup Photo

(Part 2: Test Under Dynamic Transmission Condition)

80-W5681-2 Rev. A

July 1, 2019

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Revision history

Revision	Date	Description
A	July 1, 2019	Initial release

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1 Introduction

Appendix G is created to include all photos of test setups used in Part 2 compliance test. All photos were taken with actual equipment under test (EUT) of Samsung portable handset (FCC ID: A3LSMN976V).

2 EUT Surface Definition

Figure 5-1 with actual EUT in Section 5.1 of Part 2 report is shown below:

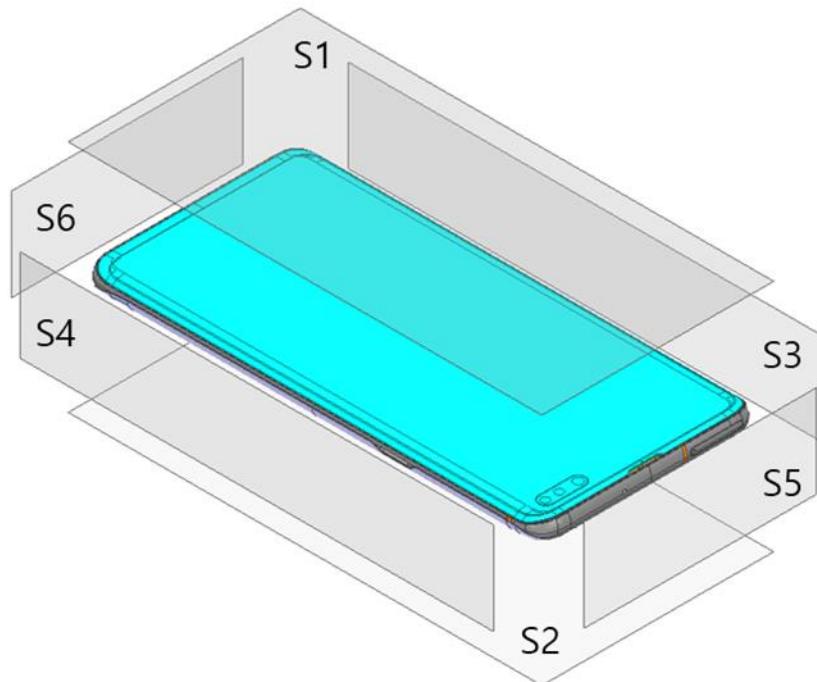
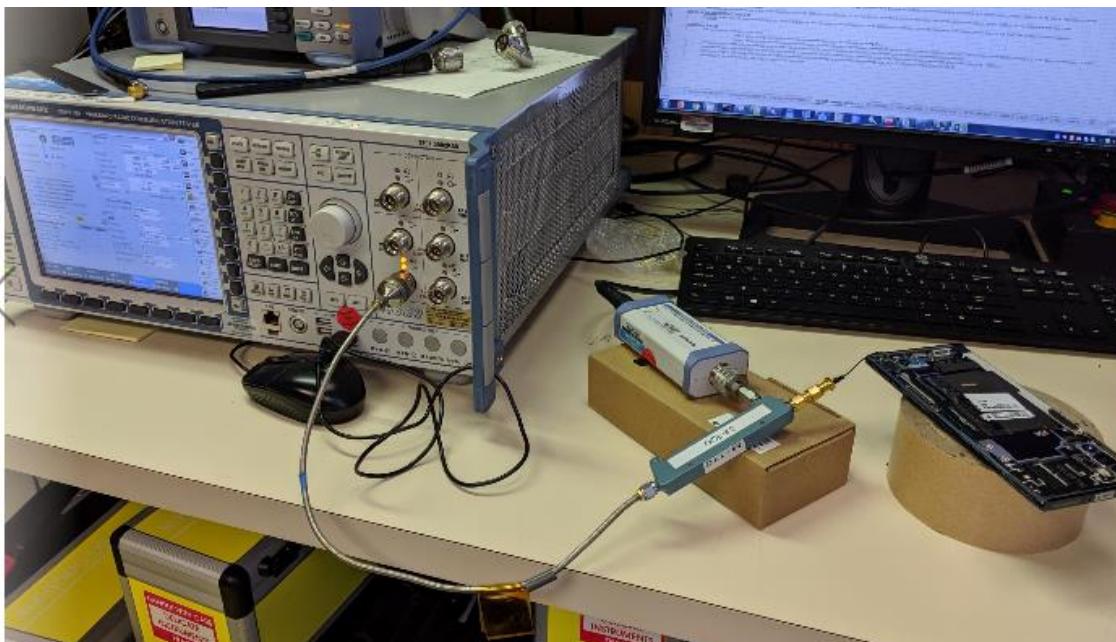


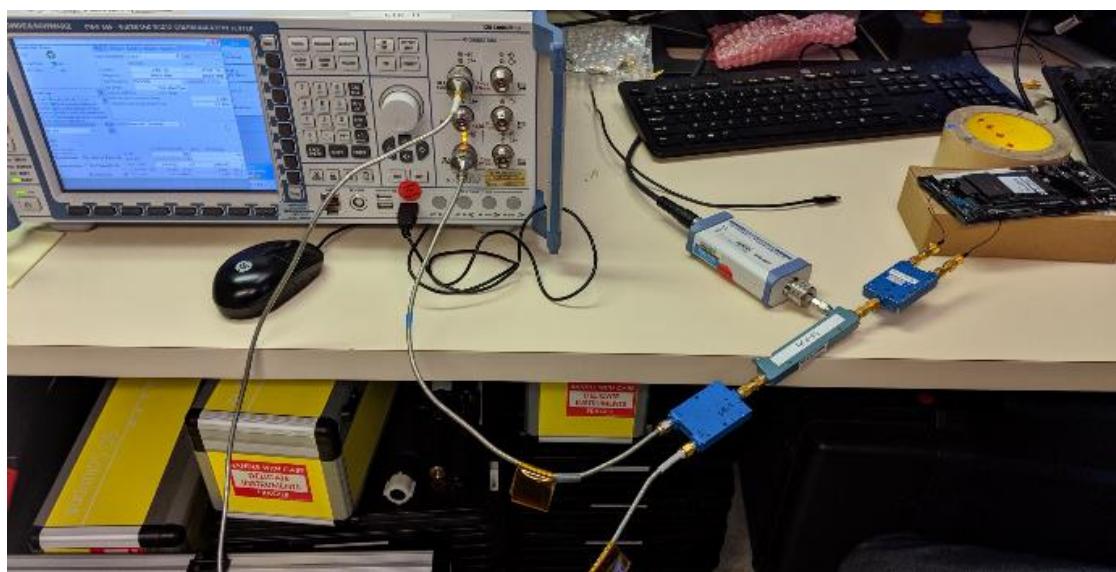
Figure 2-1: Samsung EUT position description: S1 = front, S2 = back, S3 = left, S4 = right, S5 = top, S6 = bottom

3 Conducted Power Test Setup for Sub-6 Smart Transmit Algorithm Validation

The photos below are Figure 6-1(a) and (b) taken with actual EUT in Section 6.1 of Part 2 report.



(a)



(b)

Figure 3-1 Conducted power measurement setup

4 SAR Test Setup for Sub-6 Smart Transmit Algorithm Validation

The photo below is Figure 7-1 taken with actual EUT in Section 6.1 of Part 2 report.

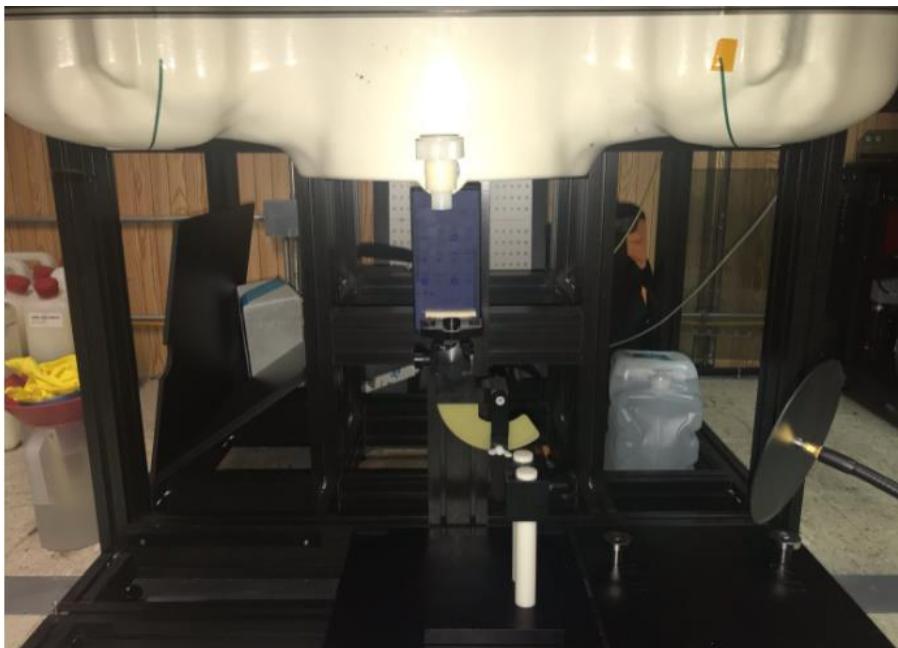
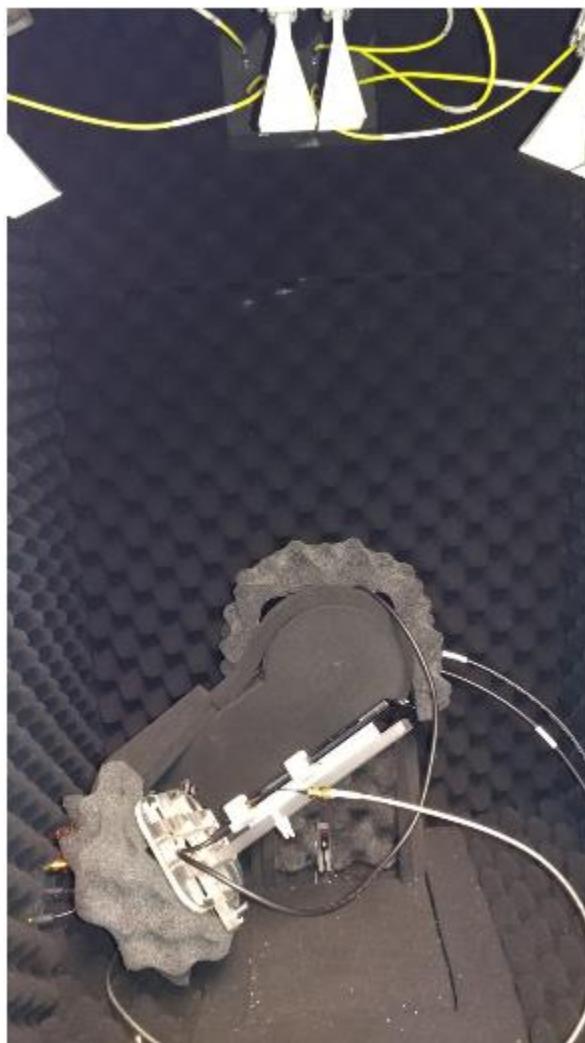


Figure 4-1 SAR measurement setup

5 Radiated Power Test Setup for mmW Smart Transmit Algorithm Validation

The photo below is Figure 8-1(a) taken with actual EUT in Section 8.1 of Part 2 report.



(a)

Figure 5-1 mmW NR radiated power measurement setup

6 PD Test Setup for mmW Smart Transmit Algorithm Validation

The photo below is Figure 9-1 taken with actual EUT in Section 8.1 of Part 2 report.

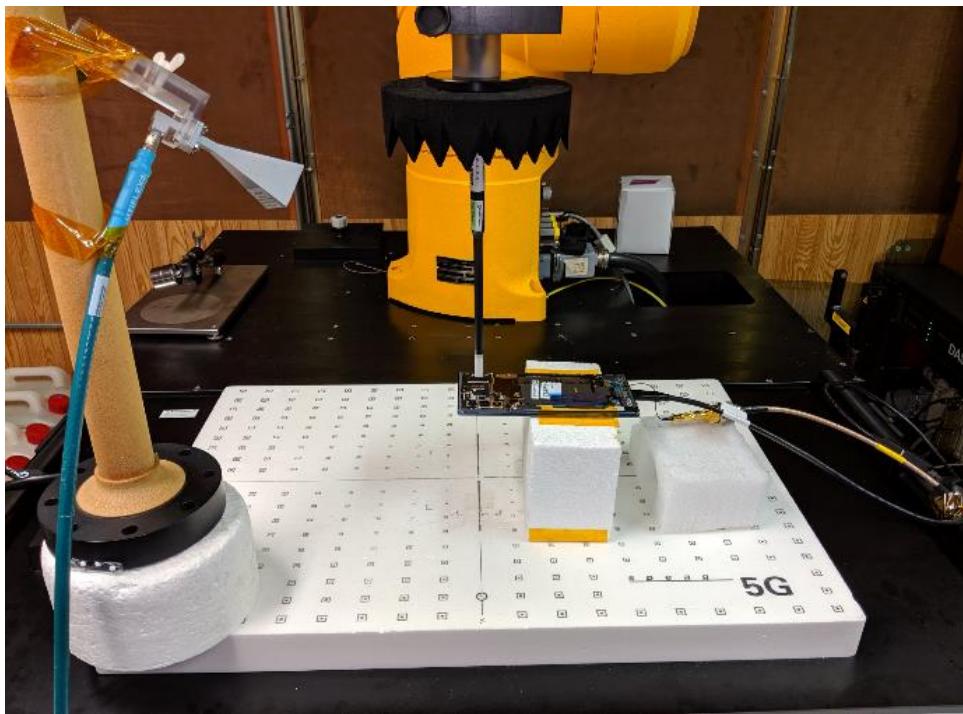


Figure 6-1 Worst-surface of EUT positioned facing up for the mmW beam being tested